

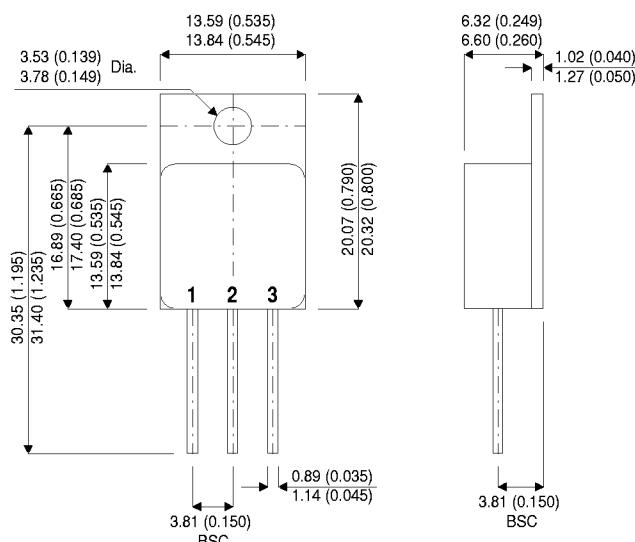


**SEME
LAB**

IRFM054

MECHANICAL DATA

Dimensions in mm (inches)



TO-254AA – Metal Package

Pin 1 – Drain

Pin 2 – Source

Pin 3 – Gate

N-CHANNEL POWER MOSFET

V_{DSS}	60V
I_{D(cont)}	35A *
R_{DS(on)}	0.027Ω

FEATURES

- HERMETICALLY SEALED ISOLATED PACKAGE
- AVALANCHE ENERGY RATING
- SIMPLE DRIVE REQUIREMENTS
- ALSO AVAILABLE IN TO-220 METAL AND SURFACE MOUNT PACKAGES
- EASE OF PARALLELING

ABSOLUTE MAXIMUM RATINGS ($T_{case} = 25^\circ\text{C}$ unless otherwise stated)

V_{GS}	Gate – Source Voltage	$\pm 20\text{V}$
I_D	Continuous Drain Current ($V_{GS} = 10\text{V}$, $T_{case} = 25^\circ\text{C}$)	35A*
I_D	Continuous Drain Current ($V_{GS} = 10\text{V}$, $T_{case} = 100^\circ\text{C}$)	35A
I_{DM}	Pulsed Drain Current ¹	220A
P_D	Power Dissipation @ $T_{case} = 25^\circ\text{C}$	150W
	Linear Derating Factor	1.2W/ $^\circ\text{C}$
E_{AS}	Single Pulse Avalanche Energy ²	480mJ
dv/dt	Peak Diode Recovery ³	4.5V/ns
T_J , T_{stg}	Operating and Storage Temperature Range	-55 to 150°C
T_L	Lead Temperature measured $1/16"$ (1.6mm) from case for 10 sec.	300°C
$R_{\theta JC}$	Thermal Resistance Junction to Case	0.83°C/W
$R_{\theta CS}$	Thermal Resistance Case to Sink (Typical)	0.21°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient	48°C/W

Notes

- 1) Repetitive Rating – Pulse width limited by Maximum Junction Temperature
 - 2) @ $V_{DD} = 25\text{V}$, $L \geq 450\mu\text{H}$, $R_G = 25\Omega$, Peak $I_L = 35\text{A}$, Starting $T_J = 25^\circ\text{C}$
 - 3) @ $I_{SD} \leq 35\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, $T_J \leq 125^\circ\text{C}$, SUGGESTED $R_G = 2.35\Omega$
- * I_D Current limited by pin diameter.



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ELECTRICAL CHARACTERISTICS ($T_{\text{amb}} = 25^\circ\text{C}$ unless otherwise stated)

Parameter	Test Conditions	Min.	Typ.	Max.	Unit
STATIC ELECTRICAL RATINGS					
BV_{DSS}	Drain – Source Breakdown Voltage $V_{GS} = 0$ $I_D = 1\text{mA}$	60			V
ΔBV_{DSS}	Temperature Coefficient of Breakdown Voltage Reference to 25°C		0.68		V/°C
$R_{DS(on)}$	Static Drain – Source On-State Resistance ² $V_{GS} = 10\text{V}$ $I_D = 35\text{A}$			0.027	Ω
$V_{GS(th)}$	Gate Threshold Voltage $V_{DS} = V_{GS}$ $I_D = 250\mu\text{A}$	2		4	V
g_{fs}	Forward Transconductance ² $V_{DS} \geq 15\text{V}$ $I_{DS} = 35\text{A}$	20			S(Ω)
I_{DSS}	Zero Gate Voltage Drain Current $V_{GS} = 0$ $V_{DS} = 0.8BV_{DSS}$ $T_J = 125^\circ\text{C}$			25	μA
I_{GSS}	Forward Gate – Source Leakage $V_{GS} = 20\text{V}$			250	nA
$ I_{GSS} $	Reverse Gate – Source Leakage $V_{GS} = -20\text{V}$			-100	
DYNAMIC CHARACTERISTICS					
C_{iss}	Input Capacitance		4600		pF
C_{oss}	Output Capacitance $V_{GS} = 0$ $V_{DS} = 25\text{V}$		2000		
C_{rss}	Reverse Transfer Capacitance $f = 1\text{MHz}$		340		
C_{DC}	Drain – Case Capacitance		12		
Q_g	Total Gate Charge $V_{GS} = 10\text{V}$	80		180	nC
Q_{gs}	Gate – Source Charge $I_D = 35\text{A}$	20		45	
Q_{gd}	Gate – Drain (“Miller”) Charge $V_{DS} = 0.5BV_{DSS}$	34		105	
$t_{d(on)}$	Turn–On Delay Time $V_{DD} = 30\text{V}$			33	
t_r	Rise Time $I_D = 35\text{A}$			180	ns
$t_{d(off)}$	Turn–Off Delay Time $R_G = 2.35\Omega$			100	
t_f	Fall Time			100	
SOURCE – DRAIN DIODE CHARACTERISTICS					
I_S	Continuous Source Current			35*	A
I_{SM}	Pulse Source Current ¹			220	
V_{SD}	Diode Forward Voltage ² $I_S = 35\text{A}$ $T_J = 25^\circ\text{C}$ $V_{GS} = 0$			2.5	V
t_{rr}	Reverse Recovery Time ² $I_F = 35\text{A}$ $T_J = 25^\circ\text{C}$			280	ns
Q_{rr}	Reverse Recovery Charge ² $d_i / d_t \leq 100\text{A}/\mu\text{s}$ $V_{DD} \leq 50\text{V}$			2.2	μC
t_{on}	Forward Turn–On Time		Negligible		
PACKAGE CHARACTERISTICS					
L_D	Internal Drain Inductance Measured from 6mm down drain lead to centre of die		8.7		nH
L_S	Internal Source Inductance Measured from 6mm down source lead to source bond pad		8.7		

PACKAGE CHARACTERISTICS

* I_S Current limited by pin diameter.